

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251154US2SRDX		SERIAL NO. 10/809,409 New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Toru TOJO, et al.		FILING DATE 26 March 2004 Herewith	
				GROUP 2886			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
/I.A./	AA 5,572,598	11/05/96	Mark J. WIHL, et al.				
/I.A./	AB 5,563,702	10/08/96	David G. EMERY, et al.				
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
/I.A./	AO 2002-501194	01/15/02	Japan				X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/I.A./	AW	Yasutaka MORIKAWA, et al., "PERFORMANCE OF CELL-SHIFT DEFECT INSPECTION TECHNIQUE", Proceedings of SPIE, Photomask and X-Ray Mask Technology IV, Vol. 3096, 1997, pgs. 404 - 414.					
	AX						
	AY						
	AZ						
				<input type="checkbox"/> Additional References sheet(s) attached			
Examiner /Isiaka Akanbi/				Date Considered 04/03/2008			

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.